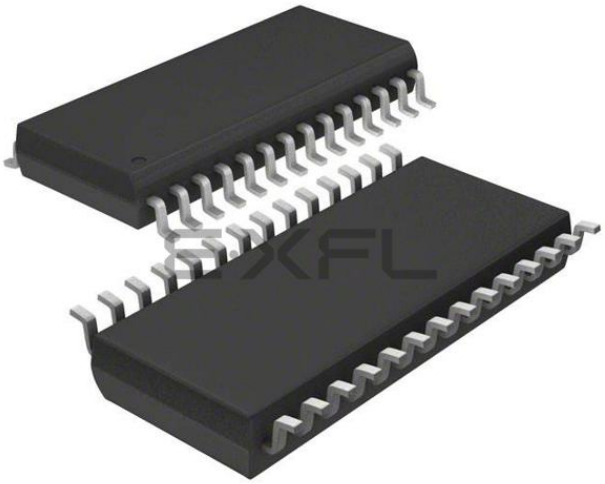


Welcome to E-XFL.COM

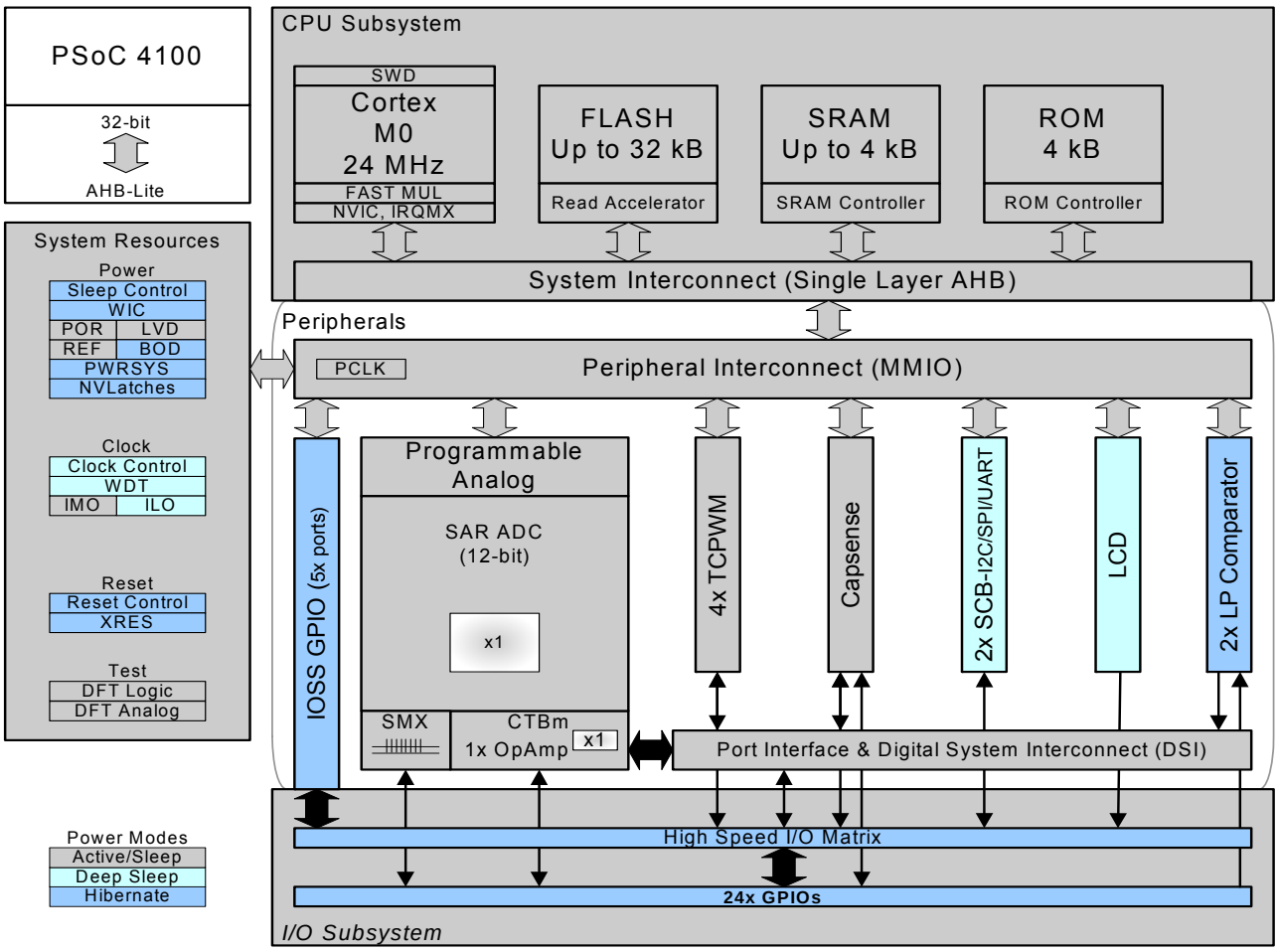
What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	24MHz
Connectivity	I²C, IrDA, LINbus, Microwire, SmartCard, SPI, SSP, UART/USART
Peripherals	Brown-out Detect/Reset, CapSense, LCD, LVD, POR, PWM, WDT
Number of I/O	24
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 8x12b SAR; D/A 2xIDAC
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	28-SSOP (0.209", 5.30mm Width)
Supplier Device Package	28-SSOP
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c4124pvs-442

Block Diagram



Functional Description

PSoC 4100 devices include extensive support for programming, testing, debugging, and tracing both hardware and firmware.

The ARM Serial_Wire Debug (SWD) interface supports all programming and debug features of the device.

Complete debug-on-chip functionality enables full device debugging in the final system using the standard production device. It does not require special interfaces, debugging pods, simulators, or emulators. Only the standard programming connections are required to fully support debug.

The PSoC Creator Integrated Development Environment (IDE) provides fully integrated programming and debug support for PSoC 4100 devices. The SWD interface is fully compatible with industry standard third party tools. With the ability to disable debug features, with very robust flash protection, and by allowing customer-proprietary functionality to be implemented in on-chip programmable blocks, the PSoC 4100 family provides a level of security not possible with multi-chip application solutions or with microcontrollers.

The debug circuits are enabled by default and can only be disabled in firmware. If not enabled, the only way to re-enable them is to erase the entire device, clear flash protection, and reprogram the device with new firmware that enables debugging.

Additionally, all device interfaces can be permanently disabled (device security) for applications concerned about phishing attacks due to a maliciously reprogrammed device or attempts to defeat security by starting and interrupting flash programming sequences. Because all programming, debug, and test interfaces are disabled when maximum device security is enabled, PSoC 4100 with device security enabled may not be returned for failure analysis. This is a trade-off the PSoC 4100 allows the customer to make.

IMO Clock Source

The IMO is the primary source of internal clocking in the PSoC 4100. It is trimmed during testing to achieve the specified accuracy. Trim values are stored in nonvolatile latches (NVL). Additional trim settings from flash can be used to compensate for changes. The IMO default frequency is 24 MHz and it can be adjusted between 3 MHz to 24 MHz in steps of 1 MHz. IMO tolerance with Cypress-provided calibration settings is ±2%.

ILO Clock Source

The ILO is a very low power oscillator, which is primarily used to generate clocks for peripheral operation in Deep Sleep mode. ILO-driven counters can be calibrated to the IMO to improve accuracy. Cypress provides a software component, which does the calibration.

Watchdog Timer

A watchdog timer is implemented in the clock block running from the ILO; this allows watchdog operation during Deep Sleep and generates a watchdog reset if not serviced before the timeout occurs. The watchdog reset is recorded in the Reset Cause register.

Reset

PSoC 4100 can be reset from a variety of sources including a software reset. Reset events are asynchronous and guarantee reversion to a known state. The reset cause is recorded in a register, which is sticky through reset and allows software to determine the cause of the Reset. An XRES pin is reserved for external reset to avoid complications with configuration and multiple pin functions during power-on or reconfiguration. The XRES pin has an internal pull-up resistor that is always enabled.

Voltage Reference

The PSoC 4100 reference system generates all internally required references. A 1% voltage reference spec is provided for the 12-bit ADC. To allow better signal-to-noise ratios (SNR) and better absolute accuracy, it is possible to bypass the internal reference using a GPIO pin or to use an external reference for the SAR.

Analog Blocks

12-bit SAR ADC

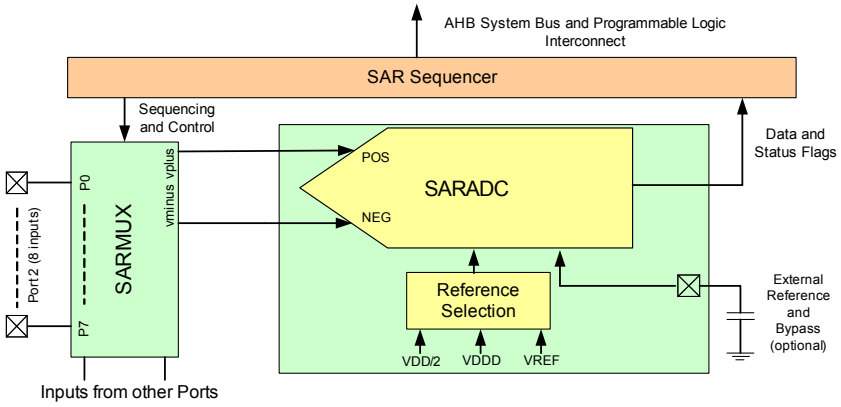
The 12-bit 806 Ksps SAR ADC can operate at a maximum clock rate of 14.5 MHz and requires a minimum of 18 clocks at that frequency to do a 12-bit conversion.

The block functionality is augmented for the user by adding a reference buffer to it (trimmable to ±1%) and by providing the choice (for the PSoC 4100 case) of three internal voltage references: V_{DD}, $V_{DD}/2$, and V_{REF} (nominally 1.024 V) as well as an external reference through a GPIO pin. The Sample-and-Hold (S/H) aperture is programmable allowing the gain bandwidth requirements of the amplifier driving the SAR inputs, which determine its settling time, to be relaxed if required. System performance will be 65 dB for true 12-bit precision providing appropriate references are used and system noise levels permit. To improve performance in noisy conditions, it is possible to provide an external bypass (through a fixed pin location) for the internal reference amplifier.

The SAR is connected to a fixed set of pins through an 8-input sequencer. The sequencer cycles through selected channels autonomously (sequencer scan) and does so with zero switching overhead (that is, aggregate sampling bandwidth is equal to 806 Ksps whether it is for a single channel or distributed over several channels). The sequencer switching is effected through a state machine or through firmware-driven switching. A feature provided by the sequencer is buffering of each channel to reduce CPU interrupt service requirements. To accommodate signals with varying source impedance and frequency, it is possible to have different sample times programmable for each channel. Also, signal range specification through a pair of range registers (low and high range values) is implemented with a corresponding out-of-range interrupt if the digitized value exceeds the programmed range; this allows fast detection of out-of-range values without the necessity of having to wait for a sequencer scan to be completed and the CPU to read the values and check for out-of-range values in software.

The SAR is able to digitize the output of the on-board temperature sensor for calibration and other temperature-dependent functions. The SAR is not available in Deep Sleep and Hibernate modes as it requires a high-speed clock (up to 18 MHz). The SAR operating range is 1.71 V to 5.5 V.

Figure 2. SAR ADC System Diagram



GPIO

PSoC 4100 has 24 GPIOs. The GPIO block implements the following:

- Eight drive strength modes:
  - Analog input mode (input and output buffers disabled)
  - Input only
  - Weak pull-up with strong pull-down
  - Strong pull-up with weak pull-down
  - Open drain with strong pull-down
  - Open drain with strong pull-up
  - Strong pull-up with strong pull-down
  - Weak pull-up with weak pull-down
- Input threshold select (CMOS or LVTTL).
- Individual control of input and output buffer enabling/disabling in addition to the drive strength modes.
- Hold mode for latching previous state (used for retaining I/O state in Deep Sleep mode and Hibernate modes).
- Selectable slew rates for dV/dt related noise control to improve EMI.

The pins are organized in logical entities called ports, which are 8-bit in width. During power-on and reset, the blocks are forced to the disable state so as not to crowbar any inputs and/or cause excess turn-on current. A multiplexing network known as a high-speed I/O matrix is used to multiplex between various signals that may connect to an I/O pin. Pin locations for fixed-function peripherals are also fixed to reduce internal multiplexing complexity.

Data output and pin state registers store, respectively, the values to be driven on the pins and the states of the pins themselves.

Every I/O pin can generate an interrupt if so enabled and each I/O port has an interrupt request (IRQ) and interrupt service routine (ISR) vector associated with it (5 for PSoC 4100).

Special Function Peripherals

LCD Segment Drive

The PSoC 4100 has an LCD controller which can drive up to four commons and up to 32 segments. It uses full digital methods to drive the LCD segments requiring no generation of internal LCD voltages. The two methods used are referred to as digital correlation and PWM.

Digital correlation pertains to modulating the frequency and levels of the common and segment signals to generate the highest RMS voltage across a segment to light it up or to keep the RMS signal zero. This method is good for STN displays but may result in reduced contrast with TN (cheaper) displays.

PWM pertains to driving the panel with PWM signals to effectively use the capacitance of the panel to provide the integration of the modulated pulse-width to generate the desired LCD voltage. This method results in higher power consumption but can result in better results when driving TN displays. LCD operation is supported during Deep Sleep refreshing a small display buffer (4 bits; 1 32-bit register per port).

CapSense

CapSense is supported on all pins in the PSoC 4100 through a CapSense Sigma-Delta (CSD) block that can be connected to any pin through an analog mux bus that any GPIO pin can be connected to via an Analog switch. CapSense function can thus be provided on any pin or group of pins in a system under software control. A component is provided for the CapSense block to make it easy for the user.

Shield voltage can be driven on another Mux Bus to provide water tolerance capability. Water tolerance is provided by driving the shield electrode in phase with the sense electrode to keep the shield capacitance from attenuating the sensed input.

The CapSense block has two IDACs which can be used for general purposes if CapSense is not being used.(both IDACs are available in that case) or if CapSense is used without water tolerance (one IDAC is available).

Pinouts

The following is the pin-list for PSoC 4100. Port 2 comprises of the high-speed Analog inputs for the SAR Mux. P1.7 is the optional external input and bypass for the SAR reference. Ports 3 and 4 contain the Digital Communication channels. All pins support CSD CapSense and Analog Mux Bus connections.

Pins		28-SSOP		Alternate Functions for Pins					Pin Description
Name	Type	Pin	Name	Analog	Alt 1	Alt 2	Alt 3	Alt 4	
VSSD	Power	DN	–	–	–	–	–	–	Digital Ground
P2.2	GPIO	5	P2.2	sarmux.2	–	–	–	–	Port 2 Pin 2: gpio, lcd, csd, sarmux
P2.3	GPIO	6	P2.3	sarmux.3	–	–	–	–	Port 2 Pin 3: gpio, lcd, csd, sarmux
P2.4	GPIO	7	P2.4	sarmux.4	tcpwm0_p[1]	–	–	–	Port 2 Pin 4: gpio, lcd, csd, sarmux, pwm
P2.5	GPIO	8	P2.5	sarmux.5	tcpwm0_n[1]	–	–	–	Port 2 Pin 5: gpio, lcd, csd, sarmux, pwm
P2.6	GPIO	9	P2.6	sarmux.6	tcpwm1_p[1]	–	–	–	Port 2 Pin 6: gpio, lcd, csd, sarmux, pwm
P2.7	GPIO	10	P2.7	sarmux.7	tcpwm1_n[1]	–	–	–	Port 2 Pin 7: gpio, lcd, csd, sarmux, pwm
P3.0	GPIO	11	P3.0	–	tcpwm0_p[0]	scb1_uart_rx[0]	scb1_i2c_scl[0]	scb1_spi_mosi[0]	Port 3 Pin 0: gpio, lcd, csd, pwm, scb1
P3.1	GPIO	12	P3.1	–	tcpwm0_n[0]	scb1_uart_tx[0]	scb1_i2c_sda[0]	scb1_spi_miso[0]	Port 3 Pin 1: gpio, lcd, csd, pwm, scb1
P3.2	GPIO	13	P3.2	–	tcpwm1_p[0]	–	swd_io	scb1_spi_clk[0]	Port 3 Pin 2: gpio, lcd, csd, pwm, scb1, swd
P3.3	GPIO	14	P3.3	–	tcpwm1_n[0]	–	swd_clk	scb1_spi_ssel_0[0]	Port 3 Pin 3: gpio, lcd, csd, pwm, scb1, swd
P4.0	GPIO	15	P4.0	–	–	scb0_uart_rx	scb0_i2c_scl	scb0_spi_mosi	Port 4 Pin 0: gpio, lcd, csd, scb0
P4.1	GPIO	16	P4.1	–	–	scb0_uart_tx	scb0_i2c_sda	scb0_spi_miso	Port 4 Pin 1: gpio, lcd, csd, scb0
P4.2	GPIO	17	P4.2	csd_c_mod	–	–	–	scb0_spi_clk	Port 4 Pin 2: gpio, lcd, csd, scb0
P4.3	GPIO	18	P4.3	csd_c_sh_tank	–	–	–	scb0_spi_ssel_0	Port 4 Pin 3: gpio, lcd, csd, scb0
P0.0	GPIO	19	P0.0	comp1_inp	–	–	–	scb0_spi_ssel_1	Port 0 Pin 0: gpio, lcd, csd, scb0, comp
P0.1	GPIO	20	P0.1	comp1_inn	–	–	–	scb0_spi_ssel_2	Port 0 Pin 1: gpio, lcd, csd, scb0, comp
P0.2	GPIO	21	P0.2	comp2_inp	–	–	–	scb0_spi_ssel_3	Port 0 Pin 2: gpio, lcd, csd, scb0, comp
P0.3	GPIO	22	P0.3	comp2_inn	–	–	–	–	Port 0 Pin 3: gpio, lcd, csd, comp
P0.6	GPIO	23	P0.6	–	ext_clk	–	–	scb1_spi_clk[1]	Port 0 Pin 6: gpio, lcd, csd, scb1, ext_clk
P0.7	GPIO	24	P0.7	–	–	–	wakeup	scb1_spi_ssel_0[1]	Port 0 Pin 7: gpio, lcd, csd, scb1, wakeup
XRES	XRES	25	XRES	–	–	–	–	–	Chip reset, active low
VCCD	Power	26	VCCD	–	–	–	–	–	Regulated supply, connect to 1 µF cap or 1.8 V
VDDD	Power	27	VDDD	–	–	–	–	–	Common power supply (Analog & Digital) 1.8 V–5.5 V
VSSA	Power	28(DN)	VSS	–	–	–	–	–	Analog Ground
P1.0	GPIO	1	P1.0	ctb.oa0.inp	tcpwm2_p[1]	–	–	–	Port 1 Pin 0: gpio, lcd, csd, ctb, pwm
P1.1	GPIO	2	P1.1	ctb.oa0.inm	tcpwm2_n[1]	–	–	–	Port 1 Pin 1: gpio, lcd, csd, ctb, pwm
P1.2	GPIO	3	P1.2	ctb.oa0.out	tcpwm3_p[1]	–	–	–	Port 1 Pin 2: gpio, lcd, csd, ctb, pwm
P1.7	GPIO	4	P1.7	ctb.oa1.inp_alt ext_vref	–	–	–	–	Port 1 Pin 7: gpio, lcd, csd, ext_ref

Notes:

1. tcpwm_p and tcpwm_n refer to tcpwm non-inverted and inverted outputs respectively.
2. P3.2 and P3.3 are SWD pins after boot (reset).

Descriptions of the pin functions are as follows:

VDDD: Power supply for both analog and digital sections (where there is no V_{DDA} pin).

Development Support

The PSoC 4100 family has a rich set of documentation, development tools, and online resources to assist you during your development process. Visit www.cypress.com/go/psoc4 to find out more.

Documentation

A suite of documentation supports the PSoC 4100 family to ensure that you can find answers to your questions quickly. This section contains a list of some of the key documents.

Software User Guide: A step-by-step guide for using PSoC Creator. The software user guide shows you how the PSoC Creator build process works in detail, how to use source control with PSoC Creator, and much more.

Component Datasheets: The flexibility of PSoC allows the creation of new peripherals (components) long after the device has gone into production. Component data sheets provide all of the information needed to select and use a particular component, including a functional description, API documentation, example code, and AC/DC specifications.

Application Notes: PSoC application notes discuss a particular application of PSoC in depth; examples include brushless DC motor control and on-chip filtering. Application notes often include example projects in addition to the application note document.

Technical Reference Manual: The Technical Reference Manual (TRM) contains all the technical detail you need to use a PSoC device, including a complete description of all PSoC registers. The TRM is available in the Documentation section at www.cypress.com/psoc4.

Online

In addition to print documentation, the Cypress PSoC forums connect you with fellow PSoC users and experts in PSoC from around the world, 24 hours a day, 7 days a week.

Tools

With industry standard cores, programming, and debugging interfaces, the PSoC 4100 family is part of a development tool ecosystem. Visit us at www.cypress.com/go/psoccreator for the latest information on the revolutionary, easy to use PSoC Creator IDE, supported third party compilers, programmers, debuggers, and development kits.

Table 3. DC Specifications *(continued)*

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
Sleep Mode, V_{DD} = 1.7 V to 5.5 V							
SID25	I_{DD20}	I^2C wakeup, WDT, and Comparators on. 6 MHz.	–	1.3	1.8	mA	V_{DD} = 1.71 V to 5.5 V
SID25A	I_{DD20A}	I^2C wakeup, WDT, and Comparators on. 12 MHz.	–	1.7	2.2	mA	V_{DD} = 1.71 V to 5.5 V
Deep Sleep Mode, V_{DD} = 1.8 V to 3.6 V (Regulator on)							
SID31	I_{DD26}	I^2C wakeup and WDT on.	–	1.3	–	µA	T = 25 °C
SID32	I_{DD27}	I^2C wakeup and WDT on.	–	–	45	µA	T = 85 °C
Deep Sleep Mode, V_{DD} = 3.6 V to 5.5 V							
SID34	I_{DD29}	I^2C wakeup and WDT on	–	1.5	15	µA	Typ. at 25 °C Max at 85 °C
Deep Sleep Mode, V_{DD} = 1.71 V to 1.89 V (Regulator bypassed)							
SID37	I_{DD32}	I^2C wakeup and WDT on.	–	1.7	–	µA	T = 25 °C
SID38	I_{DD33}	I^2C wakeup and WDT on	–	–	60	µA	T = 85 °C
Deep Sleep Mode, +105 °C							
SID33Q	I_{DD28Q}	I^2C wakeup and WDT on. Regulator Off.	–	–	135	µA	V_{DD} = 1.71 V to 1.89 V
SID34Q	I_{DD29Q}	I^2C wakeup and WDT on.	–	–	180	µA	V_{DD} = 1.8 V to 3.6 V
SID35Q	I_{DD30Q}	I^2C wakeup and WDT on.	–	–	140	µA	V_{DD} = 3.6 V to 5.5 V
Hibernate Mode, V_{DD} = 1.8 V to 3.6 V (Regulator on)							
SID40	I_{DD35}	GPIO & Reset active	–	150	–	nA	T = 25 °C
SID41	I_{DD36}	GPIO & Reset active	–	–	1000	nA	T = 85 °C
Hibernate Mode, V_{DD} = 3.6 V to 5.5 V							
SID43	I_{DD38}	GPIO & Reset active	–	150	–	nA	T = 25 °C
Hibernate Mode, V_{DD} = 1.71 V to 1.89 V (Regulator bypassed)							
SID46	I_{DD41}	GPIO & Reset active	–	150	–	nA	T = 25 °C
SID47	I_{DD42}	GPIO & Reset active	–	–	1000	nA	T = 85 °C
Hibernate Mode, +105 °C							
SID42Q	I_{DD37Q}	Regulator Off	–	–	19.4	µA	V_{DD} = 1.71 V to 1.89 V
SID43Q	I_{DD38Q}		–	–	17	µA	V_{DD} = 1.8 V to 3.6 V
SID44Q	I_{DD39Q}		–	–	16	µA	V_{DD} = 3.6 V to 5.5 V
Stop Mode							
SID304	I_{DD43A}	Stop Mode current; V_{DD} = 3.3 V	–	20	80	nA	Typ at 25 °C. Max at 85 °C
		Stop Mode current; V_{DD} = 5.5 V	–	20	750	nA	Typ at 25 °C Max at 85 °C
Stop Mode, +105 °C							
SID304Q	I_{DD43AQ}	Stop Mode current; V_{DD} = 3.6 V	–	–	5645	nA	
XRES current							
SID307	I_{DD_XR}	Supply current while XRES asserted	–	2	5	mA	

GPIO

Table 4. GPIO DC Specifications

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
SID57	V_{IH}[2]	Input voltage high threshold	0.7 × V_{DDD}	–	–	V	CMOS Input
SID58	V_{IL}	Input voltage low threshold	–	–	0.3 × V_{DDD}	V	CMOS Input
SID241	V_{IH}[2]	LVTTL input, V_{DDD} < 2.7 V	0.7× V_{DDD}	–	–	V	
SID242	V_{IL}	LVTTL input, V_{DDD} < 2.7 V	–	–	0.3 × V_{DDD}	V	
SID243	V_{IH}[2]	LVTTL input, $V_{DDD} \geq 2.7$ V	2.0	–	–	V	
SID244	V_{IL}	LVTTL input, $V_{DDD} \geq 2.7$ V	–	–	0.8	V	
SID59	V_{OH}	Output voltage high level	V_{DDD} –0.6	–	–	V	I_{OH} = 4 mA at 3 V V_{DDD}
SID60	V_{OH}	Output voltage high level	V_{DDD} –0.5	–	–	V	I_{OH} = 1 mA at 1.8 V V_{DDD}
SID61	V_{OL}	Output voltage low level	–	–	0.6	V	I_{OL} = 4 mA at 1.8 V V_{DDD}
SID62	V_{OL}	Output voltage low level	–	–	0.6	V	I_{OL} = 8 mA at 3 V V_{DDD}
SID62A	V_{OL}	Output voltage low level	–	–	0.4	V	I_{OL} = 3 mA at 3 V V_{DDD}
SID63	R_{PULLUP}	Pull-up resistor	3.5	5.6	8.5	kΩ	
SID64	$R_{PULLDOWN}$	Pull-down resistor	3.5	5.6	8.5	kΩ	
SID65	I_{IL}	Input leakage current (absolute value)	–	–	2	nA	25 °C, V_{DDD} = 3.0 V
SID65A	I_{IL_CTBM}	Input leakage current (absolute value) for CTBM pins	–	–	4	nA	
SID66	C_{IN}	Input capacitance	–	–	7	pF	
SID67	V_{HYSTTL}	Input hysteresis LVTTL	25	40	–	mV	$V_{DDD} \geq 2.7$ V. Guaranteed by characterization
SID68	$V_{HYSCMOS}$	Input hysteresis CMOS	0.05 × V_{DDD}	–	–	mV	Guaranteed by characterization
SID69	I_{DIODE}	Current through protection diode to V_{DD}/Vss	–	–	100	µA	Guaranteed by characterization
SID69A	I_{TOT_GPIO}	Maximum total source or sink chip current	–	–	200	mA	Guaranteed by characterization

Note
2. V_{IH} must not exceed V_{DDD} + 0.2 V.

Table 5. GPIO AC Specifications (Guaranteed by Characterization)

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
SID70	T_{RISEF}	Rise time in fast strong mode	2	–	12	ns	3.3-V V_{DDD}, Cload = 25 pF
SID71	T_{FALLF}	Fall time in fast strong mode	2	–	12	ns	3.3-V V_{DDD}, Cload = 25 pF
SID72	T_{RISES}	Rise time in slow strong mode	10	–	60		3.3-V V_{DDD}, Cload = 25 pF
SID73	T_{FALLS}	Fall time in slow strong mode	10	–	60		3.3-V V_{DDD}, Cload = 25 pF
SID74	$F_{GPIOUT1}$	GPIO Fout;3.3 V ≤ V_{DDD} ≤ 5.5 V. Fast strong mode.	–	–	24	MHz	90/10%, 25-pF load, 60/40 duty cycle
SID75	$F_{GPIOUT2}$	GPIO Fout;1.7 V≤ V_{DDD}≤ 3.3 V. Fast strong mode.	–	–	16.7	MHz	90/10%, 25-pF load, 60/40 duty cycle
SID76	$F_{GPIOUT3}$	GPIO Fout;3.3 V ≤ V_{DDD} ≤ 5.5 V. Slow strong mode.	–	–	7	MHz	90/10%, 25-pF load, 60/40 duty cycle
SID245	$F_{GPIOUT4}$	GPIO Fout;1.7 V ≤ V_{DDD} ≤ 3.3 V. Slow strong mode.	–	–	3.5	MHz	90/10%, 25-pF load, 60/40 duty cycle
SID246	F_{GPIOIN}	GPIO input operating frequency; 1.71 V ≤ V_{DDD} ≤ 5.5 V	–	–	24	MHz	90/10% V_{IO}

XRES

Table 6. XRES DC Specifications

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
SID77	V_{IH}	Input voltage high threshold	0.7 × V_{DDD}	–	–	V	CMOS Input
SID78	V_{IL}	Input voltage low threshold	–	–	0.3 × V_{DDD}	V	CMOS Input
SID79	R_{PULLUP}	Pull-up resistor	3.5	5.6	8.5	kΩ	
SID80	C_{IN}	Input capacitance	–	3	–	pF	
SID81	$V_{HYSXRES}$	Input voltage hysteresis	–	100	–	mV	Guaranteed by characterization
SID82	I_{DIODE}	Current through protection diode to V_{DDD}/V_{SS}	–	–	100	µA	Guaranteed by characterization

Table 7. XRES AC Specifications

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
SID83	$T_{RESETWIDTH}$	Reset pulse width	1	–	–	µs	Guaranteed by characterization

Analog Peripherals

Opamp

Table 8. Opamp Specifications (Guaranteed by Characterization)

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
	I_{DD}	Opamp block current. No load.	–	–	–	–	
SID269	I_{DD_HI}	Power = high	–	1100	1850	µA	
SID270	I_{DD_MED}	Power = medium	–	550	950	µA	
SID271	I_{DD_LOW}	Power = low	–	150	350	µA	
	GBW	Load = 20 pF, 0.1 mA. V_{DDA} = 2.7 V	–	–	–	–	
SID272	GBW_HI	Power = high	6	–	–	MHz	
SID273	GBW_MED	Power = medium	4	–	–	MHz	
SID274	GBW_LO	Power = low	–	1	–	MHz	
	I_{OUT_MAX}	$V_{DDA} \geq 2.7$ V, 500 mV from rail	–	–	–	–	
SID275	$I_{OUT\_MAX\_HI}$	Power = high	10	–	–	mA	
SID276	$I_{OUT\_MAX\_MID}$	Power = medium	10	–	–	mA	
SID277	$I_{OUT\_MAX\_LO}$	Power = low	–	5	–	mA	
	I_{OUT}	V_{DDA} = 1.71 V, 500 mV from rail	–	–	–	–	
SID278	$I_{OUT\_MAX\_HI}$	Power = high	4	–	–	mA	
SID279	$I_{OUT\_MAX\_MID}$	Power = medium	4	–	–	mA	
SID280	$I_{OUT\_MAX\_LO}$	Power = low	–	2	–	mA	
SID281	V_{IN}	Charge pump on, $V_{DDA} \geq 2.7$ V	–0.05	–	V_{DDA} – 0.2	V	
SID282	V_{CM}	Charge pump on, $V_{DDA} \geq 2.7$ V	–0.05	–	V_{DDA} – 0.2	V	
	V_{OUT}	$V_{DDA} \geq 2.7$ V	–	–	–		
SID283	V_{OUT_1}	Power = high, Iload=10 mA	0.5	–	V_{DDA} – 0.5	V	
SID284	V_{OUT_2}	Power = high, Iload=1 mA	0.2	–	V_{DDA} – 0.2	V	
SID285	V_{OUT_3}	Power = medium, Iload=1 mA	0.2	–	V_{DDA} – 0.2	V	
SID286	V_{OUT_4}	Power = low, Iload=0.1mA	0.2	–	V_{DDA} – 0.2	V	
SID288	V_{OS_TR}	Offset voltage, trimmed	1	±0.5	1	mV	High mode
SID288A	V_{OS_TR}	Offset voltage, trimmed	–	±1	–	mV	Medium mode
SID288B	V_{OS_TR}	Offset voltage, trimmed	–	±2	–	mV	Low mode
SID290	$V_{OS\_DR\_TR}$	Offset voltage drift, trimmed	–10	±3	10	µV/°C	High mode $T_A \leq 85$ °C.
SID290Q	$V_{OS\_DR\_TR}$	Offset voltage drift, trimmed	–15	±3	15	µV/°C	High mode. $T_A \leq 105$ °C
SID290A	$V_{OS\_DR\_TR}$	Offset voltage drift, trimmed	–	±10	–	µV/°C	Medium mode
SID290B	$V_{OS\_DR\_TR}$	Offset voltage drift, trimmed	–	±10	–	µV/°C	Low mode
SID291	CMRR	DC	70	80	–	dB	V_{DDD} = 3.6 V
SID292	PSRR	At 1 kHz, 100 mV ripple	70	85	–	dB	V_{DDD} = 3.6 V
	Noise		–	–	–	–	
SID293	V_{N1}	Input referred, 1 Hz - 1GHz, power = high	–	94	–	µVrms	
SID294	V_{N2}	Input referred, 1 kHz, power = high	–	72	–	nV/rtHz	
SID295	V_{N3}	Input referred, 10 kHz, power = high	–	28	–	nV/rtHz	
SID296	V_{N4}	Input referred, 100 kHz, power = high	–	15	–	nV/rtHz	

Table 8. Opamp Specifications (Guaranteed by Characterization) *(continued)*

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
SID297	Cload	Stable up to maximum load. Performance specs at 50 pF.	–	–	125	pF	
SID298	Slew_rate	Cload = 50 pF, Power = High, $V_{DDA} \geq$ 2.7 V	6	–	–	V/µs	
SID299	T_op_wake	From disable to enable, no external RC dominating	–	300	–	µs	
	Comp_mode	Comparator mode; 50 mV drive, Trise = Tfall (approx.)	–	–	–		
SID299A	OL_GAIN	Open Loop Gain	–	90	–	dB	Guaranteed by design
SID300	T_{PD1}	Response time; power = high	–	150	–	ns	
SID301	T_{PD2}	Response time; power = medium	–	400	–	ns	
SID302	T_{PD3}	Response time; power = low	–	2000	–	ns	
SID303	Vhyst_op	Hysteresis	–	10	–	mV	

Comparator

Table 9. Comparator DC Specifications

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
SID85	$V_{OFFSET2}$	Input offset voltage, Common Mode voltage range from 0 to V_{DD}-1	–	–	±4	mV	
SID85A	$V_{OFFSET3}$	Input offset voltage. Ultra low-power mode ($V_{DDD} \geq$ 2.2 V for Temp < 0 °C, $V_{DDD} \geq$ 1.8 V for Temp > 0 °C)	–	±12	–	mV	
SID86	V_{HYST}	Hysteresis when enabled, Common Mode voltage range from 0 to V_{DD} -1.	–	10	35	mV	Guaranteed by characterization
SID87	V_{ICM1}	Input common mode voltage in normal mode	0	–	V_{DDD} – 0.1	V	Modes 1 and 2
SID247	V_{ICM2}	Input common mode voltage in low power mode ($V_{DDD} \geq$ 2.2 V for Temp < 0 °C, $V_{DDD} \geq$ 1.8 V for Temp > 0 °C)	0	–	V_{DDD}	V	
SID247A	V_{ICM3}	Input common mode voltage in ultra low power mode	0	–	V_{DDD} – 1.15	V	
SID88	CMRR	Common mode rejection ratio	50	–	–	dB	$V_{DDD} \geq$ 2.7 V. Guaranteed by characterization
SID88A	CMRR	Common mode rejection ratio	42	–	–	dB	$V_{DDD} <$ 2.7 V. Guaranteed by characterization
SID89	I_{CMP1}	Block current, normal mode	–	–	400	µA	Guaranteed by characterization
SID248	I_{CMP2}	Block current, low power mode	–	–	100	µA	Guaranteed by characterization
SID259	I_{CMP3}	Block current, ultra low power mode ($V_{DDD} \geq$ 2.2 V for Temp < 0 °C, $V_{DDD} \geq$ 1.8 V for Temp > 0 °C)	–	6	28	µA	Guaranteed by characterization
SID90	Z_{CMP}	DC input impedance of comparator	35	–	–	MΩ	Guaranteed by characterization

Table 10. Comparator AC Specifications

(Guaranteed by Characterization)

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID91	T_{RESP1}	Response time, normal mode	–	–	110	ns	50 mV overdrive
SID258	T_{RESP2}	Response time, low power mode	–	–	200	ns	50 mV overdrive
SID92	T_{RESP3}	Response time, ultra low power mode (V_{DDD} ≥ 2.2 V for Temp < 0 °C, V_{DDD} ≥ 1.8 V for Temp > 0 °C)	–	–	15	µs	200 mV overdrive

Temperature Sensor

Table 11. Temperature Sensor Specifications

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID93	$T_{SENSACC}$	Temperature sensor accuracy	–5	±1	+5	°C	–40 to +85 °C

SAR ADC

Table 12. SAR ADC DC Specifications

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID94	A_RES	Resolution	–	–	12	bits	
SID95	A_CHNIS_S	Number of channels - single ended	–	–	8		8 full speed
SID96	A-CHNKS_D	Number of channels - differential	–	–	4		Diff inputs use neighboring I/O
SID97	A-MONO	Monotonicity	–	–	–		Yes. Based on characterization
SID98	A_GAINERR	Gain error	–	–	±0.1	%	With external reference. Guaranteed by characterization
SID99	A_OFFSET	Input offset voltage	–	–	2	mV	Measured with 1-V $V_{REF.}$ Guaranteed by characterization
SID100	A_ISAR	Current consumption	–	–	1	mA	
SID101	A_VINS	Input voltage range - single ended	V_{SS}	–	V_{DDA}	V	Based on device characterization
SID102	A_VIND	Input voltage range - differential	V_{SS}	–	V_{DDA}	V	Based on device characterization
SID103	A_INRES	Input resistance	–	–	2.2	KΩ	Based on device characterization
SID104	A_INCAP	Input capacitance	–	–	10	pF	Based on device characterization

Table 13. SAR ADC AC Specifications (Guaranteed by Characterization)

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID106	A_PSRR	Power supply rejection ratio	70	–	–	dB	
SID107	A_CMRR	Common mode rejection ratio	66	–	–	dB	Measured at 1 V
SID108	A_SAMP_1	Sample rate with external reference bypass cap	–	–	1	Msps	
SID108A	A_SAMP_2	Sample rate with no bypass cap. Reference = V_{DD}	–	–	806	Ksps	
SID108B	A_SAMP_3	Sample rate with no bypass cap. Internal reference	–	–	100	Ksps	
SID109	A_SNDR	Signal-to-noise and distortion ratio (SINAD)	65	–	–	dB	F_{IN} = 10 kHz
SID111	A_INL	Integral non linearity	–1.7	–	+2	LSB	V_{DD} = 1.71 to 5.5, 806 Ksps, Vref = 1 to 5.5. –40 °C ≤ T_A ≤ 85 °C
			–1.9	–	+2	LSB	V_{DD} = 1.71 to 5.5, 806 Ksps, Vref = 1 to 5.5. –40 °C ≤ T_A ≤ 105 °C
SID111A	A_INL	Integral non linearity	–1.5	–	+1.7	LSB	V_{DDD} = 1.71 to 3.6, 806 Ksps, Vref = 1.71 to V_{DDD}. –40 °C ≤ T_A ≤ 85 °C
			–1.9	–	+2	LSB	V_{DDD} = 1.71 to 3.6, 806 Ksps, Vref = 1.71 to V_{DDD}. –40 °C ≤ T_A ≤ 105 °C
SID111B	A_INL	Integral non linearity	–1.5	–	+1.7	LSB	V_{DDD} = 1.71 to 5.5, 500 Ksps, Vref = 1 to 5.5.
SID112	A_DNL	Differential non linearity	–1	–	+2.2	LSB	V_{DDD} = 1.71 to 5.5, 806 Ksps, Vref = 1 to 5.5. –40 °C ≤ T_A ≤ 85 °C
			–1	–	+2.3	LSB	V_{DDD} = 1.71 to 5.5, 806 Ksps, Vref = 1 to 5.5. –40 °C ≤ T_A ≤ 105 °C
SID112A	A_DNL	Differential non linearity	–1	–	+2	LSB	V_{DDD} = 1.71 to 3.6, 806 Ksps, Vref = 1.71 to V_{DDD}. –40 °C ≤ T_A ≤ 85 °C
			–1	–	+2.2	LSB	V_{DDD} = 1.71 to 3.6, 806 Ksps, Vref = 1.71 to V_{DDD}. –40 °C ≤ T_A ≤ 105 °C
SID112B	A_DNL	Differential non linearity	–1	–	+2.2	LSB	V_{DDD} = 1.71 to 5.5, 500 Ksps, Vref = 1 to 5.5.
SID113	A_THD	Total harmonic distortion	–	–	–65	dB	F_{IN} = 10 kHz.

CSD

Table 14. CSD Block Specification

Spec ID#	Parameter	Description	Min	Typ	Max	Units	Details/ Conditions
CSD Specification							
SID308	VCSD	Voltage range of operation	1.71	–	5.5	V	
SID309	IDAC1	DNL for 8-bit resolution	–1	–	1	LSB	
SID310	IDAC1	INL for 8-bit resolution	–3	–	3	LSB	
SID311	IDAC2	DNL for 7-bit resolution	–1	–	1	LSB	
SID312	IDAC2	INL for 7-bit resolution	–3	–	3	LSB	
SID313	SNR	Ratio of counts of finger to noise. Guaranteed by characterization	5	–	–	Ratio	Capacitance range of 9 to 35 pF, 0.1 pF sensitivity
SID314	IDAC1_CRT1	Output current of Idac1 (8-bits) in High range	–	612	–	µA	
SID314A	IDAC1_CRT2	Output current of Idac1(8-bits) in Low range	–	306	–	µA	
SID315	IDAC2_CRT1	Output current of Idac2 (7-bits) in High range	–	304.8	–	µA	
SID315A	IDAC2_CRT2	Output current of Idac2 (7-bits) in Low range	–	152.4	–	µA	

Digital Peripherals

The following specifications apply to the Timer/Counter/PWM peripherals in the Timer mode.

Timer/Counter/PWM

Table 15. TCPWM Specifications

(Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID.TCPWM.1	ITCPWM1	Block current consumption at 3 MHz	–	–	45	µA	All modes (Timer/Counter/PWM)
SID.TCPWM.2	ITCPWM2	Block current consumption at 12 MHz	–	–	155	µA	All modes (Timer/Counter/PWM)
SID.TCPWM.2A	ITCPWM3	Block current consumption at 48 MHz	–	–	650	µA	All modes (Timer/Counter/PWM)
SID.TCPWM.3	TCPWMFREQ	Operating frequency	–	–	Fc	MHz	Fc max = Fcpu. Maximum = 24 MHz
SID.TCPWM.4	TPWMENEXT	Input Trigger Pulse Width for all Trigger Events	2/Fc	–	–	ns	Trigger Events can be Stop, Start, Reload, Count, Capture, or Kill depending on which mode of operation is selected.
SID.TCPWM.5	TPWMEXT	Output Trigger Pulse widths	2/Fc	–	–	ns	Minimum possible width of Overflow, Underflow, and CC (Counter equals Compare value) trigger outputs
SID.TCPWM.5A	TCRES	Resolution of Counter	1/Fc	–	–	ns	Minimum time between successive counts
SID.TCPWM.5B	PWMRES	PWM Resolution	1/Fc	–	–	ns	Minimum pulse width of PWM Output
SID.TCPWM.5C	QRES	Quadrature inputs resolution	1/Fc	–	–	ns	Minimum pulse width between Quadrature phase inputs.

I^2C

Table 16. Fixed I^2C DC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID149	I_{I2C1}	Block current consumption at 100 kHz	–	–	50	µA	
SID150	I_{I2C2}	Block current consumption at 400 kHz	–	–	135	µA	
SID151	I_{I2C3}	Block current consumption at 1 Mbps	–	–	310	µA	
SID152	I_{I2C4}	I^2C enabled in Deep Sleep mode	–	–	1.4	µA	

Table 17. Fixed I^2C AC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID153	F_{I2C1}	Bit rate	–	–	1	Mbps	

LCD Direct Drive

Table 18. LCD Direct Drive DC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID154	I_{LCDLOW}	Operating current in low power mode	–	5	–	µA	16 × 4 small segment disp. at 50 Hz
SID155	C_{LCDCAP}	LCD capacitance per segment/common driver	–	500	5000	pF	Guaranteed by Design
SID156	LCD_{OFFSET}	Long-term segment offset	–	20	–	mV	
SID157	I_{LCDOP1}	PWM Mode current. 5-V bias. 24-MHz IMO. 25 °C	–	0.6	–	mA	32 × 4 segments. 50 Hz
SID158	I_{LCDOP2}	PWM Mode current. 3.3-V bias. 24-MHz IMO. 25 °C	–	0.5	–	mA	32 × 4 segments. 50 Hz

Table 19. LCD Direct Drive AC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID159	F_{LCD}	LCD frame rate	10	50	150	Hz	

Table 20. Fixed UART DC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID160	I_{UART1}	Block current consumption at 100 Kbits/sec	–	–	55	µA	
SID161	I_{UART2}	Block current consumption at 1000 Kbits/sec	–	–	312	µA	

Table 21. Fixed UART AC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units
SID162	F_{UART}	Bit rate	–	–	1	Mbps

SPI Specifications

Table 22. Fixed SPI DC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units
SID163	I_{SPI1}	Block current consumption at 1 Mbits/sec	–	–	360	µA
SID164	I_{SPI2}	Block current consumption at 4 Mbits/sec	–	–	560	µA
SID165	I_{SPI3}	Block current consumption at 8 Mbits/sec	–	–	600	µA

Table 23. Fixed SPI AC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units
SID166	F_{SPI}	SPI operating frequency (master; 6X oversampling)	–	–	4	MHz

Table 24. Fixed SPI Master mode AC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units
SID167	T_{DMO}	MOSI valid after Sclock driving edge	–	–	15	ns
SID168	T_{DSI}	MISO valid before Sclock capturing edge. Full clock, late MISO Sampling used	20	–	–	ns
SID169	T_{HMO}	Previous MOSI data hold time with respect to capturing edge at Slave	0	–	–	ns

Table 25. Fixed SPI Slave mode AC Specifications (Guaranteed by Characterization)

Spec ID	Parameter	Description	Min	Typ	Max	Units
SID170	T_{DMI}	MOSI valid before Sclock capturing edge	40	–	–	ns
SID171	T_{DSO}	MISO valid after Sclock driving edge	–	–	42 + (3 × Tscbclk)	ns
SID171A	T_{DSO_ext}	MISO valid after Sclock driving edge in Ext. Clock mode	–	–	48	ns
SID172	T_{HSO}	Previous MISO data hold time	0	–	–	ns
SID172A	$T_{SSELSCK}$	SSEL Valid to first SCK Valid edge	100	–	–	ns

Memory

Table 26. Flash DC Specifications

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID173	V_{PE}	Erase and program voltage	1.71	–	5.5	V	

Table 27. Flash AC Specifications

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID174	$T_{ROWWRITE}$[3]	Row (block) write time (erase and program)	–	–	20	ms	Row (block) = 128 bytes. –40 °C ≤ T_A ≤ 85 °C
			–	–	26	ms	Row (block) = 128 bytes. –40 °C ≤ T_A ≤ 105 °C
SID175	$T_{ROWERASE}$[3]	Row erase time	–	–	13	ms	
SID176	$T_{ROWPROGRAM}$[3]	Row program time after erase	–	–	7	ms	–40 °C ≤ T_A ≤ 85 °C
			–	–	13	ms	–40 °C ≤ T_A ≤ 105 °C
SID178	$T_{BULKERASE}$[3]	Bulk erase time (32 KB)	–	–	35	ms	
SID180	$T_{DEVPROG}$[3]	Total device program time	–	–	7	seconds	Guaranteed by characterization
SID181	F_{END}	Flash endurance	100 K	–	–	cycles	Guaranteed by characterization
SID182	F_{RET}	Flash retention. $T_A \leq 55$ °C, 100 K P/E cycles	20	–	–	years	Guaranteed by characterization
SID182A		Flash retention. $T_A \leq 85$ °C, 10 K P/E cycles	10	–	–	years	Guaranteed by characterization
SID182B	F_{RETQ}	Flash retention. $T_A \leq 105$ °C, 10K P/E cycles, ≤ three years at $T_A \geq 85$ °C.	10	20	–		Guaranteed by character-ization.

System Resources

Power-on-Reset (POR) with Brown Out

Table 28. Imprecise Power On Reset (PRES)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID185	$V_{RISEIPOR}$	Rising trip voltage	0.80	–	1.45	V	Guaranteed by characterization
SID186	$V_{FALLIPOR}$	Falling trip voltage	0.75	–	1.4	V	Guaranteed by characterization
SID187	$V_{IPORHYST}$	Hysteresis	15	–	200	mV	Guaranteed by characterization

Table 29. Precise Power On Reset (POR)

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID190	$V_{FALLPPOR}$	BOD trip voltage in active and sleep modes	1.64	–	–	V	Full functionality between 1.71 V and BOD trip voltage is guaranteed by characterization
SID192	$V_{FALLDPSLP}$	BOD trip voltage in Deep Sleep	1.4	–	–	V	Guaranteed by characterization
BID55	Svdd	Maximum power supply ramp rate	–	–	67	kV/sec	

Note
3. It can take as much as 20 milliseconds to write to Flash. During this time the device should not be Reset, or Flash operations will be interrupted and cannot be relied on to have completed. Reset sources include the XRES pin, software resets, CPU lockup states and privilege violations, improper power supply levels, and watchdogs. Make certain that these are not inadvertently activated.

Voltage Monitors

Table 30. Voltage Monitors DC Specifications

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID195	V_{LVI1}	LVI_A/D_SEL[3:0] = 0000b	1.71	1.75	1.79	V	
SID196	V_{LVI2}	LVI_A/D_SEL[3:0] = 0001b	1.76	1.80	1.85	V	
SID197	V_{LVI3}	LVI_A/D_SEL[3:0] = 0010b	1.85	1.90	1.95	V	
SID198	V_{LVI4}	LVI_A/D_SEL[3:0] = 0011b	1.95	2.00	2.05	V	
SID199	V_{LVI5}	LVI_A/D_SEL[3:0] = 0100b	2.05	2.10	2.15	V	
SID200	V_{LVI6}	LVI_A/D_SEL[3:0] = 0101b	2.15	2.20	2.26	V	
SID201	V_{LVI7}	LVI_A/D_SEL[3:0] = 0110b	2.24	2.30	2.36	V	
SID202	V_{LVI8}	LVI_A/D_SEL[3:0] = 0111b	2.34	2.40	2.46	V	
SID203	V_{LVI9}	LVI_A/D_SEL[3:0] = 1000b	2.44	2.50	2.56	V	
SID204	V_{LVI10}	LVI_A/D_SEL[3:0] = 1001b	2.54	2.60	2.67	V	
SID205	V_{LVI11}	LVI_A/D_SEL[3:0] = 1010b	2.63	2.70	2.77	V	
SID206	V_{LVI12}	LVI_A/D_SEL[3:0] = 1011b	2.73	2.80	2.87	V	
SID207	V_{LVI13}	LVI_A/D_SEL[3:0] = 1100b	2.83	2.90	2.97	V	
SID208	V_{LVI14}	LVI_A/D_SEL[3:0] = 1101b	2.93	3.00	3.08	V	
SID209	V_{LVI15}	LVI_A/D_SEL[3:0] = 1110b	3.12	3.20	3.28	V	
SID210	V_{LVI16}	LVI_A/D_SEL[3:0] = 1111b	4.39	4.50	4.61	V	
SID211	LVI_IDD	Block current	–	–	100	µA	Guaranteed by characterization

Table 31. Voltage Monitors AC Specifications

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID212	$T_{MONTRIP}$	Voltage monitor trip time	–	–	1	µs	Guaranteed by characterization

SWD Interface

Table 32. SWD Interface Specifications

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID213	F_SWDCLK1	$3.3\ V \le V_{DD} \le 5.5\ V$	–	–	14	MHz	SWDCLK ≤ 1/3 CPU clock frequency
SID214	F_SWDCLK2	$1.71\ V \le V_{DD} \le 3.3\ V$	–	–	7	MHz	SWDCLK ≤ 1/3 CPU clock frequency
SID215	T_SWDI_SETUP	T = 1/f SWDCLK	0.25*T	–	–	ns	Guaranteed by characterization
SID216	T_SWDI_HOLD	T = 1/f SWDCLK	0.25*T	–	–	ns	Guaranteed by characterization
SID217	T_SWDO_VALID	T = 1/f SWDCLK	–	–	0.5*T	ns	Guaranteed by characterization
SID217A	T_SWDO_HOLD	T = 1/f SWDCLK	1	–	–	ns	Guaranteed by characterization

Table 38. Block Specs

Spec ID	Parameter	Description	Min	Typ	Max	Units	Details/Conditions
SID257	T_{WS24}*	Number of wait states at 24 MHz	0	–	–		CPU execution from Flash. Guaranteed by characterization
SID260	V_{REFSAR}	Trimmed internal reference to SAR	–1	–	+1	%	Percentage of Vbg (1.024 V). Guaranteed by characterization
SID262	$T_{CLKSWITCH}$	Clock switching from clk1 to clk2 in clk1 periods	3	–	4	Periods	Guaranteed by design
* Tws24 is guaranteed by design.							

Document Conventions

Units of Measure

Table 45. Units of Measure

Symbol	Unit of Measure
°C	degrees Celsius
dB	decibel
fF	femto farad
Hz	hertz
KB	1024 bytes
kbps	kilobits per second
Khr	kilohour
kHz	kilohertz
kΩ	kilo ohm
Ksps	kilosamples per second
LSB	least significant bit
Mbps	megabits per second
MHz	megahertz
MΩ	mega-ohm
Msps	megasamples per second
µA	microampere
µF	microfarad
µH	microhenry
µs	microsecond
µV	microvolt
µW	microwatt
mA	milliampere
ms	millisecond
mV	millivolt
nA	nanoampere
ns	nanosecond
nV	nanovolt
Ω	ohm
pF	picofarad
ppm	parts per million
ps	picosecond
s	second
sps	samples per second
sqrtHz	square root of hertz
V	volt

Document History Page *(continued)*

Document Title: Automotive PSoC® 4: PSoC 4100 Family Datasheet Programmable System-on-Chip (PSoC®) Document Number: 001-93576				
Revision	**ECN**	**Orig. of Change**	**Submission Date**	**Description of Change**
*D (cont.)	5331416	MVRE	07/04/2016	Updated Electrical Specifications: Updated System Resources: Updated Power-on-Reset (POR) with Brown Out: Updated Table 29: Updated details in “Details/Conditions” column corresponding to $V_{FALLPPOR}$ parameter. Added Svdd parameter and its details. Updated Internal Main Oscillator: Updated Table 34: Updated details in “Details/Conditions” column corresponding to $F_{IMOTOL1}$ parameter. Updated Internal Low-Speed Oscillator: Updated Table 36: Updated details in “Details/Conditions” column corresponding to $F_{ILOTRIM1}$ parameter. Updated Packaging: Updated description. Updated to new template. Completing Sunset Review.
*E	5675099	SNPR	03/28/2017	Updated Ordering Information.